

Intel[®] 7 Series / C216 Chipset Platform Controller Hub (PCH)

Thermal Mechanical Specifications and Design Guidelines (TMSDG)

June 2012



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Revision History

Revision Number	Description	Revision Date
001	<ul style="list-style-type: none">Initial release	April 2012
002	<ul style="list-style-type: none">Added Intel® C216 Chipset Platform Controller Hub (PCH)	May 2012
003	<ul style="list-style-type: none">Added Desktop Intel® Q77, Q75 Express Chipsets	June 2012

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1 Introduction

The goals of this document are to:

- Outline the thermal and mechanical operating limits and specifications for the Intel® 7 Series Chipset and Intel® C216 Chipset for use in single processor systems for Desktop and Server / Workstation.
- Describe reference thermal solutions that meet the specifications of the Intel® 7 Series Chipset and Intel® C216 Chipset.

The Intel® 7 Series Chipset and Intel® C216 Chipset components supported in this document are:

- Intel® Z77 Express Chipset
- Intel® Z75 Express Chipset
- Intel® H77 Express Chipset
- Intel® B75 Express Chipset
- Intel® Q77 Express Chipset
- Intel® Q75 Express Chipset
- Intel® C216 Chipset

Note:

Unless otherwise specified, the term “Platform Controller Hub” or “PCH” will be used to refer to any version of the chipset for Desktop or Server / Workstation. Only where required will a specific product code be used.

Properly designed thermal solutions provide adequate cooling to maintain the Platform Controller Hub case (or junction) temperatures at or below thermal specifications. This is accomplished by providing a low local-ambient temperature, ensuring adequate local airflow, and minimizing the case to local-ambient thermal resistance. By maintaining the PCH case (or junction) temperature at or below the specified limits, a system designer can ensure the proper functionality, performance, and reliability of the PCH. Operation outside the functional limits can cause data corruption or permanent damage to the component.

The simplest and most cost-effective method to improve the inherent system cooling characteristics is through careful chassis design and placement of fans, vents, and ducts. When additional cooling is required, component thermal solutions may be implemented in conjunction with system thermal solutions. The size of the fan or heatsink can be varied to balance size and space constraints with acoustic noise.



1.0.1 Related Documents

The reader of this specification should also be familiar with material and concepts presented in the following documents.

Title	Location
<i>Intel® 7 Series / C216 Chipset Platform Controller Hub (PCH) Datasheet</i>	326776
<i>Intel® 7 Series / C216 Chipset Platform Controller Hub (PCH) Specification Update</i>	326777
<i>Thermally Advantaged Chassis Design Guidelines</i>	http://www3.intel.com/cd/channel/reseller/asmo-na/eng/products/53211.htm
Various system thermal design suggestions	http://www.formfactors.org

1.1 Terminology

Item	Description
BLT	Bond Line Thickness. Final settled thickness of the thermal interface material after installation of the heatsink.
CTE	Coefficient of Thermal Expansion. The relative rate a material expands during a thermal event.
FC-BGA	Flip Chip Ball Grid Array. A package type defined by a plastic substrate where a die is mounted using an underfill C4 (Controlled Collapse Chip Connection) attach style. The primary electrical interface is an array of solder balls attached to the substrate opposite the die. The device arrives at the customer with solder balls attached.
MD	Metal Defined pad is one where a pad is individually etched into the PCB with a minimum width trace exiting it.
PCH	Platform Controller Hub. The PCH is connected to the processor using the Direct Media Interface (DMI) and the Intel® Flexible Display Interface (Intel® FDI).
SMD	The Solder Mask Defined pad is typically a pad in a flood plane where the solder mask opening defines the pad size for soldering to the component.
TDP	Thermal design power. Thermal solutions should be designed to dissipate this power level. TDP is not the peak power that the PCH can dissipate.
TIM	Thermal Interface Material. A conductive material used between the component and heatsink to improve thermal conduction.
TMTV	Thermal Mechanical Test Vehicle. A mechanically equivalent package that contains a resistive heater in the die to evaluate thermal solutions. The package has daisy chain connections for use in evaluation of solder joint reliability.

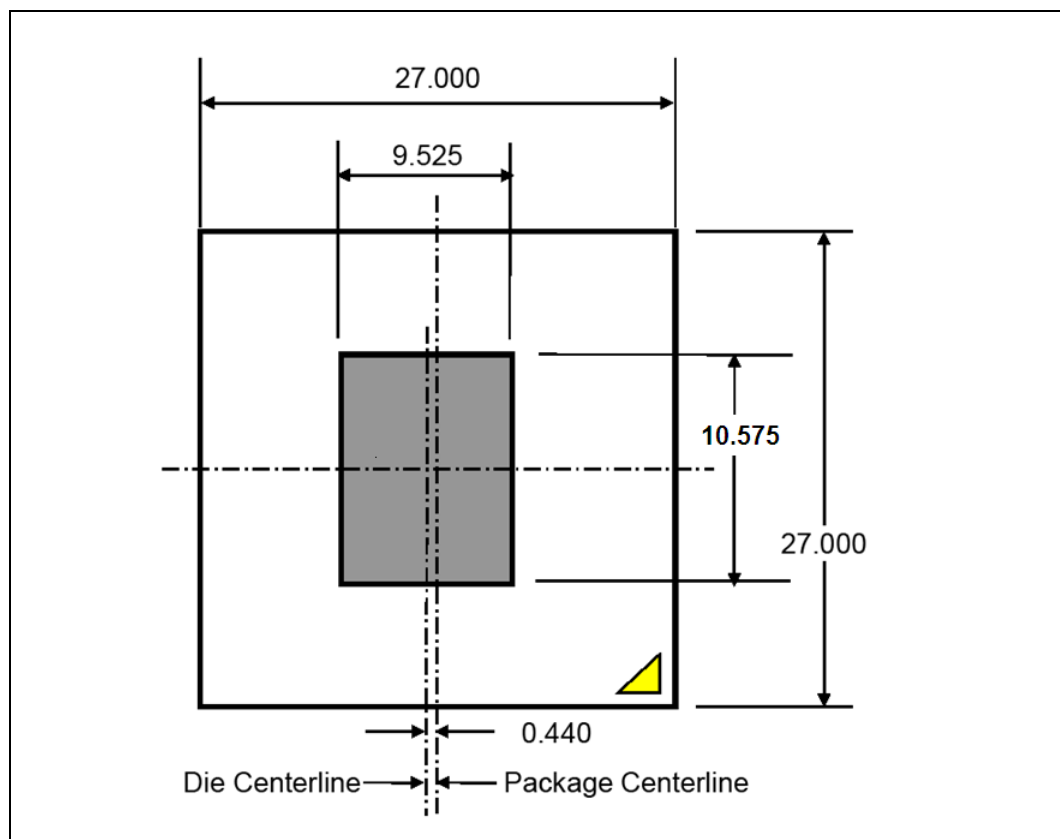


2 Packaging Mechanical Specifications

2.1 PCH Package for Single Processor Desktop or Server and Workstation

The Platform Controller Hub uses a 27 mm square flip chip ball grid array (FC-BGA) package (see [Figure 2-1](#) through [Figure 2-3](#)). The complete package drawing can be found in [Appendix B](#).

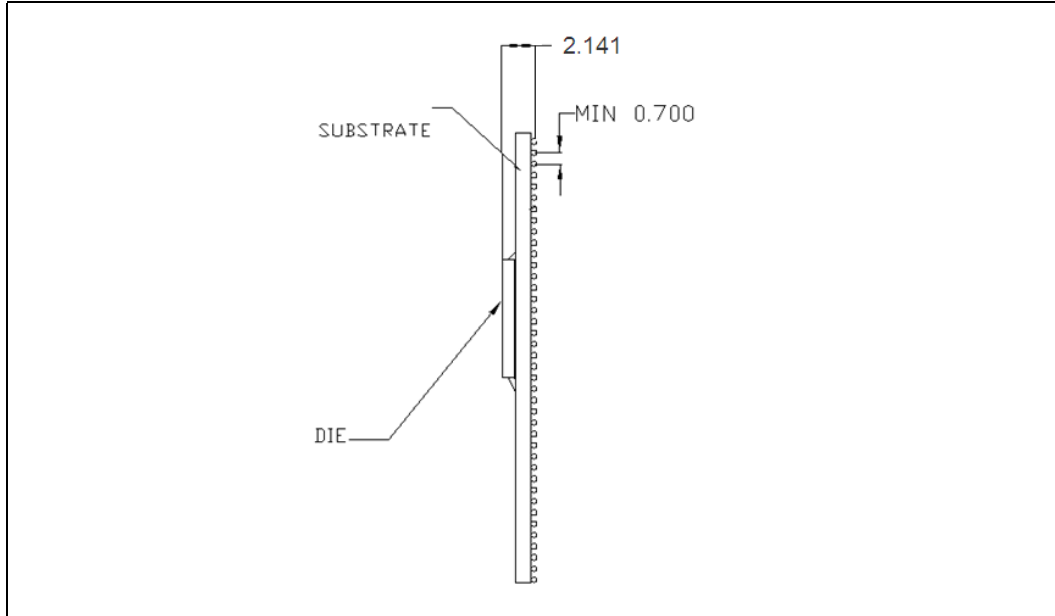
Figure 2-1. Package Dimensions (Top View)



NOTE:

1. All dimensions in mm

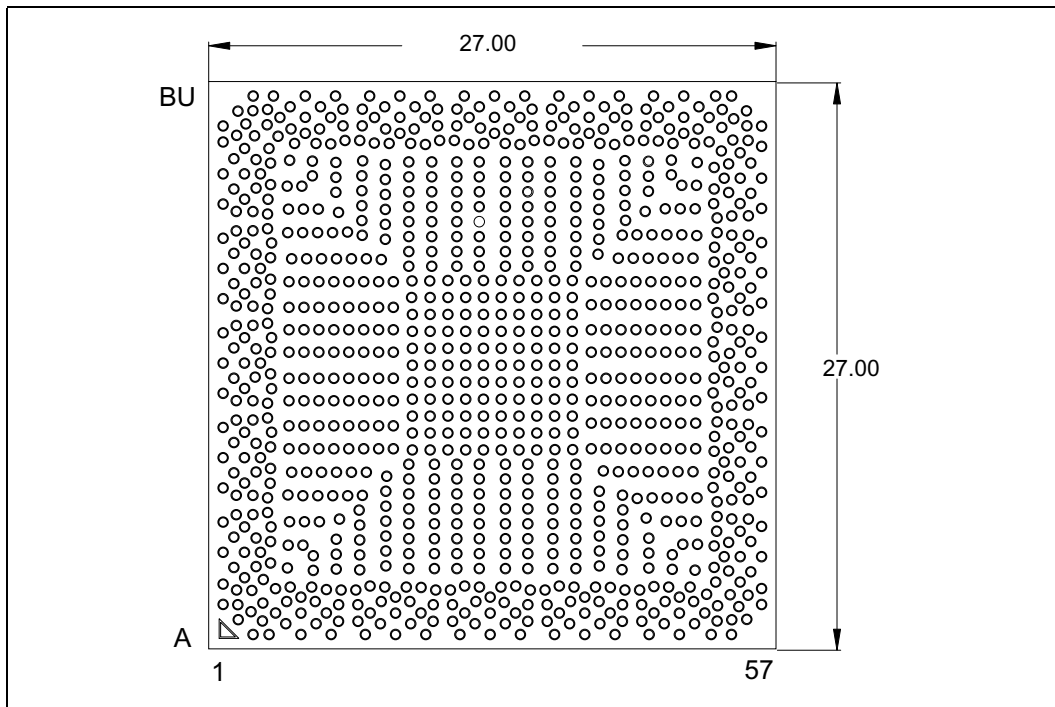
Figure 2-2. Package Dimensions (Side View)



NOTE:

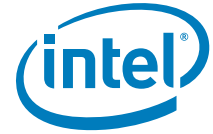
1. All dimensions in mm

Figure 2-3. Package (Land Side View)



NOTE:

1. All dimensions in mm



2.2 Solder Balls

A total of 942 solder balls corresponding to the lands are on the bottom of the PCH package for surface mounting with the motherboard. The package solder ball has the following characteristics:

- Lead-free SAC (SnAgCu) 405 solder alloy with a silver (Ag) content between 3% and 4% and a melting temperature of approximately 217 °C. The alloy is compatible with immersion silver (ImAg) and Organic Solderability Protectant (OSP) motherboard surface finishes and a SAC alloy solder paste.
- Solder ball diameter 17 mil [0.4318 mm], before attaching to the package.

2.3 Package Mechanical Requirements

The package has a bare die that is capable of sustaining a maximum static normal load of 15 lbf (67 N). These mechanical load limits must not be exceeded during heatsink installation, mechanical stress testing, standard shipping conditions, and/or any other use condition.

Note: The heatsink attach solutions must not induce continuous stress to the package with the exception of a uniform load to maintain the heatsink-to-package thermal interface.

Note: These specifications apply to uniform compressive loading in a direction perpendicular to the die top surface.

Note: These specifications are based on limited testing for design characterization. Loading limits are for the package only.







3 Thermal Specifications

To ensure proper operation and reliability of the PCH, the case (or junction) temperature must be at or below the maximum value specified in [Table 3-1](#). System and/or component level thermal solutions are required to maintain these temperature specifications. [Chapter 5, "Thermal Metrology"](#) provides the thermal metrology guidelines for case (or junction) temperature measurements.

3.1 Thermal Design Power (TDP)

Real applications are unlikely to cause the PCH component to consume maximum power dissipation for sustained time periods. Therefore, in order to arrive at a more realistic power level for thermal design purposes, Intel characterizes power consumption to reach a Thermal Design Power (TDP). TDP is the target power level to which the thermal solutions should be designed. TDP is not the maximum power that the PCH can dissipate (see [Table 3-1](#)).

TDP condition is a set of applications when run simultaneously, would stress all its features and dissipate power equivalent to TDP in the worst leakage scenario (see [Table 3-2](#)). The configuration of PCH TDP is in [Table 3-3](#).

3.2 Thermal Specifications

The data in [Table 3-1](#) is based on pre-silicon estimates for the PCH. The TDP, Idle, S3 and S5 (deep Sx) values are based on system configuration, see the notes of [Table 3-1](#). Intel recommends designing the PCH thermal solution to the TDP for maximum flexibility and reuse. The PCH package have poor heat transfer capability into the board and have minimal thermal capability without thermal solutions. Intel requires that system designers plan for an attached heatsink when using the PCH. The reference thermal solution is described in [Chapter 6, "ATX Reference Thermal Solution"](#).

Table 3-1. PCH Thermal Specifications (Sheet 1 of 2)

Parameter	Value	Notes
T _{case-max}	104 °C	
T _{case-min}	0 °C	
T _{j,max}	108 °C	
T _{CONTROL}	104 °C	
TDP	6.7 W	<ol style="list-style-type: none"> 1. Integrated graphics on 2. The value is based on system configuration and applications running simultaneously, see Table 3-2 and Table 3-3. 3. The value measurement is based on a core voltage of 1.05 V and T_j of T_{j,max}
TDP	5.9 W	<ol style="list-style-type: none"> 1. Integrated graphics off 2. The value is based on system configuration and applications running simultaneously, see Table 3-2 and Table 3-3. 3. The value measurement is based on a core voltage of 1.05 V and T_j of T_{j,max}



Table 3-1. PCH Thermal Specifications (Sheet 2 of 2)

Parameter	Value	Notes
Idle	2.7 W	<ol style="list-style-type: none"> The value is based on system configuration, see Table 3-5 The value measurement is based on a core voltage of 1.05 V and Tj of 50 °C
Idle (configuration 2)	2.7 W	<ol style="list-style-type: none"> The value is based on system configuration, see Table 3-5 but disconnected one Gen 2 SATA HDD. The value measurement is based on a core voltage of 1.05 V and Tj of 50 °C
Idle (configuration 3)	2.1 W	<ol style="list-style-type: none"> The value is based on system configuration, see Table 3-5 but disconnected one Gen 2 SATA HDD and disabled integrated graphic and then installed an external graphic card The value measurement is based on a core voltage of 1.05 V and Tj of 50 °C
S3	0.15 W	The value measurement is based on Tj of 35 °C
Realistic (configuration 1)	5.0 W	<ol style="list-style-type: none"> Integrated GFX on The value measurement is based on TDP sample. The value measurement is based on a core voltage of 1.05V and Tj of 110 °C The value is based on system configuration and applications running simultaneously, see Table 3-4 and Table 3-5
Realistic (configuration 2)	4.4 W	<ol style="list-style-type: none"> Integrated GFX off The value measurement is based on TDP sample. The value measurement is based on a core voltage of 1.05V and Tj of 110 °C The value is based on system configuration and applications running simultaneously, see Table 3-4 and Table 3-5
S5/ deep Sx	< 0.009 W	The value measurement is based on Tj of 35 °C

Table 3-2. PCH TDP Workload Running Simultaneously

TDP Workload Description
Small File copy, OS SATA Gen2 to USB 2.0 thumb drive Printer emulation (print ASCII test file to USB thumb drive) NetBlast over LAN to emulate heavy web traffic (Local network, system 1) Large file copy from USB3.0 SSD to Gen 2 RAID0 array Large file copy from Gen 3 RAID0 array to USB3.0 SSD NetBlast over WLAN to emulate heavy web traffic (Local network, system 2) 1080P HD Video Recording over USB2.0 Large file copy from PCIE USB3.0 hub thumb drive to Gen 3 RAID0 array Small file copy from Media Card Reader to USB 2.0 thumb drive Large file copy from USB 3.0 SSD to PCIE USB3.0 hub thumb drive



Table 3-3. PCH TDP Configuration

PCH Interfaces	Connected and Active	Notes
USB Port 0	Flash Thumb drive	High-speed
USB Port 1	Flash Thumb drive	High-speed
USB Port 2	Flash Thumb drive	High-speed
USB Port 3	Flash Thumb drive	High-speed
USB Port 4	USB Keyboard	Low-speed
USB Port 5	USB Mouse	Low-speed
USB Port 6	HD Camera	High-speed
USB Port 7	Media Card Reader	High-speed
USB Port 8	Game Controller	High-speed
USB Port 9	Digital Camera	High-speed
USB3 Port 1	128 GB SSD	Super-Speed
USB3 Port 2	128 GB SSD	Super-Speed
USB3 Port 3	128 GB SSD	Super-Speed
USB3 Port 4	128 GB SSD	Super-Speed
SATA Port 0	SSD RAID0 Array 1	Gen 3
SATA Port 1	SSD RAID0 Array 1	Gen 3
SATA Port 2	SSD RAID0 Array 2	Gen 2
SATA Port 3	SSD RAID0 Array 2	Gen 2
SATA Port 4	BD ODD	Gen 1
SATA Port 5	SSD OS	Gen 2
PCIE Port 1	Lewisville Gbe	
PCIE Port 3	USB3.0 Hub	2-port
PCIE Port 6	WiFi (Mini PCIE)	
Display Link 1	DP 1920 x 1200	
Display Link 2	VGA 1920 x 1080	
Platform Audio Jacks	None	
FDI x 8	Active, x4 link width	
DMI x 4	Active	
LPC I/F	Active	
PCI 1394 Controller	Active	

Table 3-4. PCH Realistic Workload Running Simultaneously

Realistic Workload Description
Large file copy, SATA HDD#1 to SATA HDD#2 Large file copy, SATA HDD #2 to GbE (shared network drive on another PC) 1080p local video playback from SATA HDD #1



Table 3-5. PCH Idle Power Configuration

PCH Interfaces	Link Utilization	Notes
Intel High Definition Audio	Idle	External Codec
USB Port 4	EHCI1 (Idle, ports in suspend)	Full-speed Keyboard
USB Port 5		Full-speed Mouse
SATA Port 2	Windows 7 system Idle, LPM disabled	Gen 2 HDD
SATA Port 3	Windows 7 system Idle, LPM disabled	Gen 2 HDD
SATA Port 5	Windows 7 system Idle, LPM disabled	Gen 2 ODD
PCIE Port 1	100% L1	x 1 device Lewisville Gbe
PCIE Port 2	100% L1	x 1 device (IEEE-1394b Controller)
VGA	Idle	Connected-1920 x 1080

3.3 Storage Specifications

Table 3-6 includes a list of the specifications for device storage in terms of maximum and minimum temperatures and relative humidity. These conditions should not be exceeded in storage or transportation.

Table 3-6. Storage Conditions

Parameter	Description	Min	Max	Notes
T _{ABSOLUTE STORAGE}	The non-operating device storage temperature. Damage (latent or otherwise) may occur when subjected to for any length of time.	-25 °C	125 °C	1, 2, 3
T _{SUSTAINED STORAGE}	The ambient storage temperature limit (in shipping media) for a sustained period of time.	-5 °C	40 °C	4, 5
RH _{SUSTAINED STORAGE}	The maximum device storage relative humidity for a sustained period of time.	60% @ 24 °C		5, 6
TIME _{SUSTAINED STORAGE}	A prolonged or extended period of time; typically associated with customer shelf life.	0 Months	6 Months	6

NOTES:

- Refers to a component device that is not assembled in a board or socket that is not to be electrically connected to a voltage reference or I/O signals.
- Specified temperatures are based on data collected. Exceptions for surface mount reflow are specified in by applicable JEDEC standard. Non-adherence may affect component reliability.
- T_{ABSOLUTE STORAGE} applies to the unassembled component only and does not apply to the shipping media, moisture barrier bags or desiccant.
- Intel branded board products are certified to meet the following temperature and humidity limits that are given as an example only (Non-Operating Temperature Limit: -40 °C to 70 °C & Humidity: 50% to 90%, non-condensing with a maximum wet bulb of 28 °C). Post board attach storage temperature limits are not specified for non-Intel® branded boards.
- The JEDEC, J-JSTD-020 moisture level rating and associated handling practices apply to all moisture sensitive devices removed from the moisture barrier bag.
- Nominal temperature and humidity conditions and durations are given and tested within the constraints imposed by Tsustained and customer shelf life in applicable Intel box and bags.





4 Thermal Simulation

Intel provides thermal simulation models of the PCH and associated user guides to aid system designers in simulating, analyzing, and optimizing their thermal solutions in an integrated, system-level environment. The models are for use with the commercially available Computational Fluid Dynamics (CFD)-based thermal analysis tool FLOTHERM* (version 9.1 or higher) by Flomerics, Inc.* and Icepak* by Fluent*. Contact your Intel field sales representative to order the thermal models and users' guides.

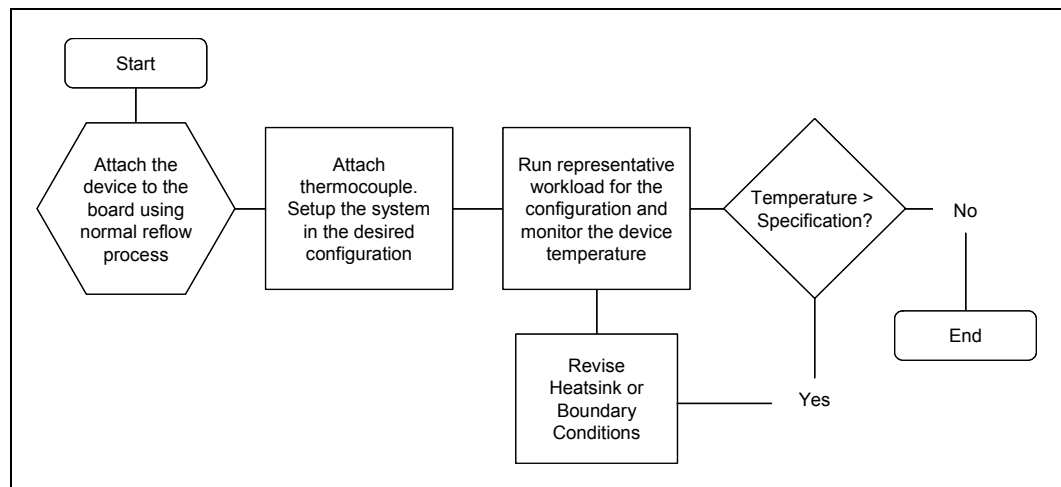




5 Thermal Metrology

The system designer must make temperature measurements to accurately determine the thermal performance of the system. Intel has established guidelines for proper techniques to measure the PCH case and junction temperatures. The flowchart in Figure 5-1 offers useful guidelines for thermal performance and evaluation.

Figure 5-1. Thermal Solution Decision Flow Chart



5.1 Tcase Temperature Measurements

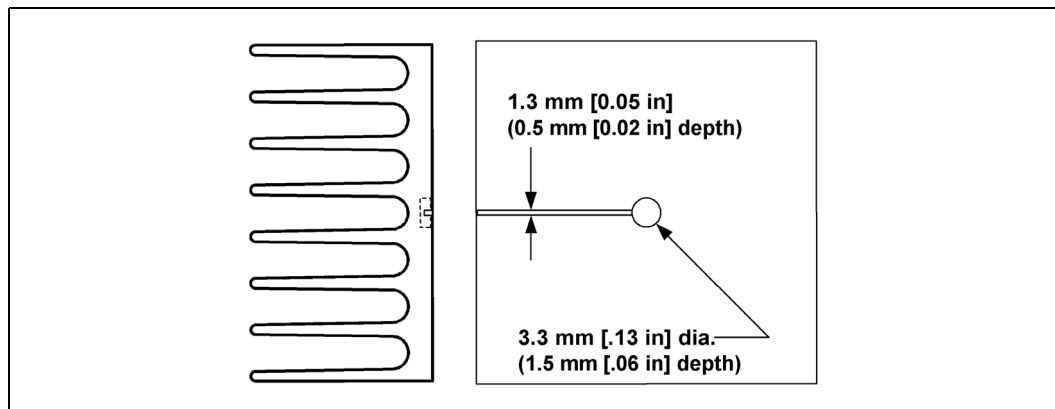
To ensure functionality and reliability, the T_{CASE} of the PCH must be maintained between the maximum/minimum operating range of the temperature specification as noted in Table 3-1. The surface temperature at the geometric center of the die corresponds to T_{CASE} . Measuring T_{CASE} requires special care to ensure an accurate temperature measurement.

Temperature differences between the surface and the surrounding local ambient air can introduce errors in the measurements. The measurement errors could be due to a poor thermal contact between the thermocouple junction and the surface of the package, heat loss by radiation and/or convection, conduction through thermocouple leads, and/or contact between the thermocouple cement and the heatsink base (if a heatsink is used). For maximum measurement accuracy, only the following thermocouple attach approach is recommended.

5.1.1 Heatsink Thermocouple Attach Methodology

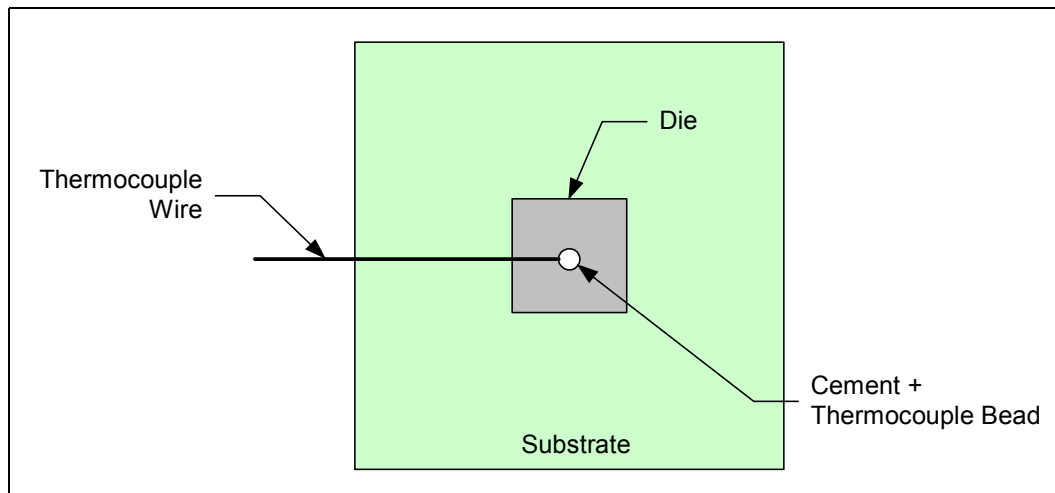
1. Mill a 3.3 mm (0.13 in.) diameter and 1.5 mm (0.06 in.) deep hole centered on the bottom of the heatsink base.
2. Mill a 1.3 mm (0.05 in.) wide and 0.5 mm (0.02 in.) deep slot from the centered hole to one edge of the heatsink. The slot should be parallel to the heatsink fins (see Figure 5-3).
3. Attach thermal interface material (TIM) to the bottom of the heatsink base.
4. Cut out portions of the TIM to make room for the thermocouple wire and bead. The cutouts should match the slot and hole milled into the heatsink base.
5. Attach a 36 gauge or smaller calibrated K-type thermocouple bead to the center of the top surface of the die using a high thermal conductivity cement. During this step, ensure no contact is present between the thermocouple cement and the heatsink base because any contact will affect the thermocouple reading. It is critical that the thermocouple bead makes contact with the die (see Figure 5-3).
6. Attach heatsink assembly to the package and route thermocouple wires out through the milled slot.

Figure 5-2. Heatsink Modifications



Note: Not to Scale

Figure 5-3. Top View of Package



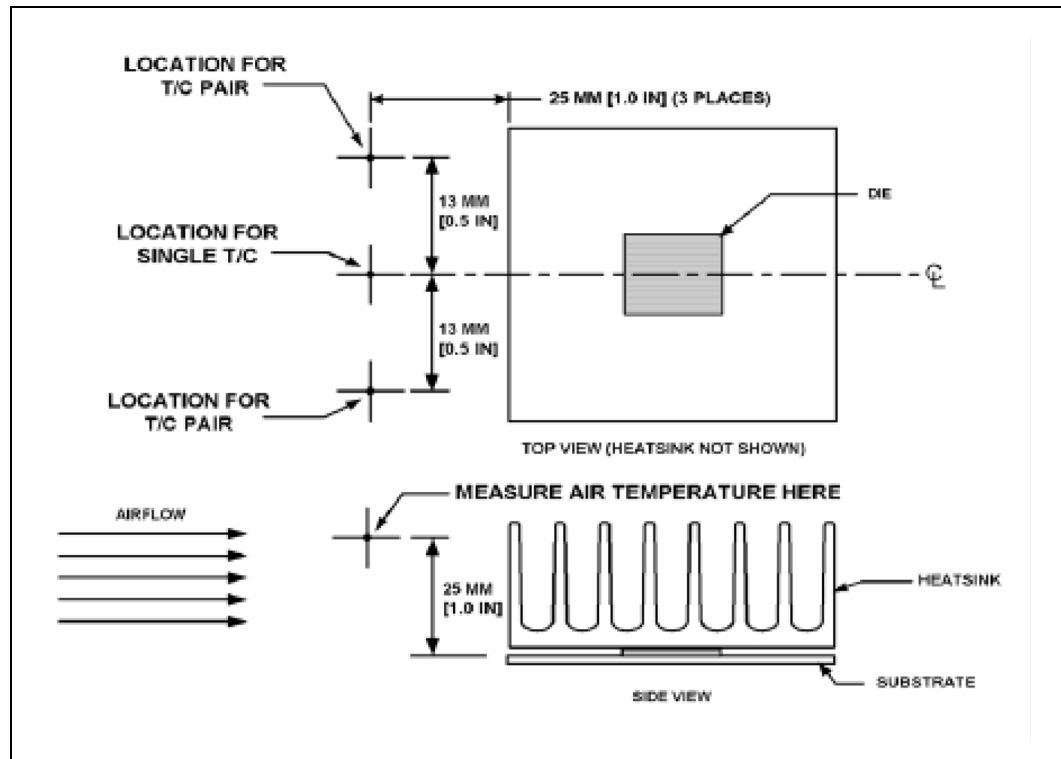
5.2 Ambient Temperature and Airflow Measurement

Figure 5-4 describes the recommended location for air temperature measurements measured relative to the component. For a more accurate measurement of the average approach air temperature, Intel recommends averaging temperatures recorded from two thermocouples spaced about 25 mm [1.0 in] apart. Locations for both a single thermocouple and a pair of thermocouples are presented.

Airflow velocity should be measured using industry standard air velocity sensors. Typical airflow sensor technology may include hot wire anemometers.

Figure 5-4 provides guidance for airflow velocity measurement locations. These locations are for a typical JEDEC test setup and may not be compatible with all chassis layouts due to the proximity of the, PCI and PCI Express* add-in cards to the component. The user may have to adjust the locations for a specific chassis. Be aware that sensors may need to be aligned perpendicular to the airflow velocity vector or an inaccurate measurement may result. Measurements should be taken with the chassis fully sealed in its operational configuration to achieve a representative airflow profile within the chassis.

Figure 5-4. Airflow and Temperature Measurement Locations



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6 ATX Reference Thermal Solution

Note: The reference thermal mechanical solution information shown in this document represents the current state of the design. The data is subject to modification and represents design targets, not commitments by Intel.

The design strategy for the PCH thermal solution is to reuse the z-clip heatsink designed from Intel® 5 Series Chipset and used on subsequent PCH designs through Intel® 7 Series Chipset.

This section describes the overall requirements for the ATX heatsink reference thermal solution including critical-to-function dimensions, operating environment, and validation criteria. Other chipset components may or may not need attached thermal solutions depending on your specific system local-ambient operating conditions.

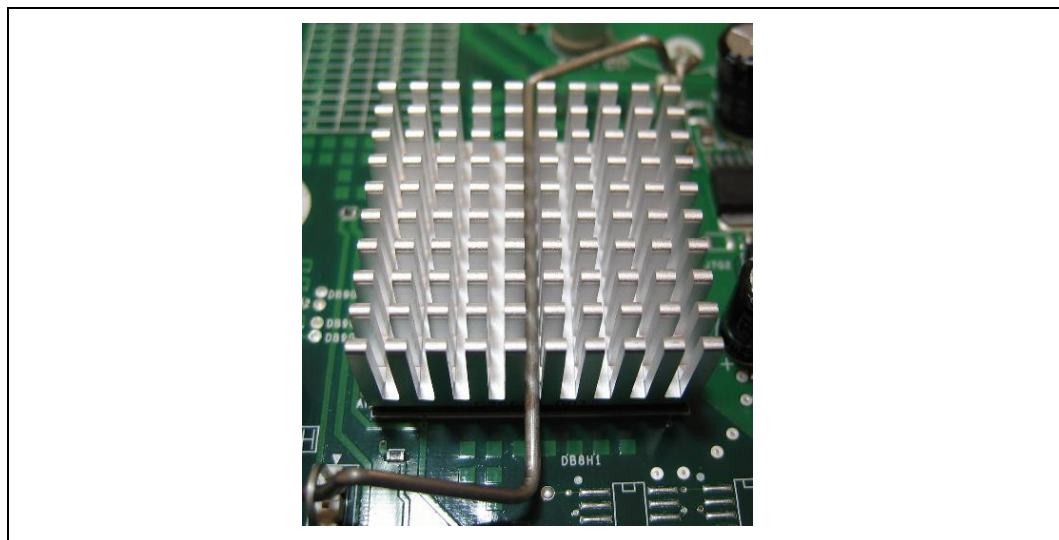
6.1 Reference Solution

The reference solution is an extruded aluminum heatsink with pre-applied phase change thermal interface material (TIM). The TIM is a Chomerics T710. The reference solution is provided as an assembly with the clip, TIM, and extrusion. See [Appendix B](#) for the complete set of mechanical drawings including the motherboard keep out zone.

The reference design z-clip centers the load on the die and by design will keep the heatsink flush and parallel with the top surface of the die. The TIM size in the reference design is larger than the die area. The resistivity of the TIM is 5×10^{16} Ohm-cm. Any TIM material that comes in contact with die side capacitors (DSC) will not cause a short.

During the heatsink assembly process, the heatsink may come in contact with DSC. The maximum spring force allowed for the reference design z-clip has not been shown to cause damage to DSC during assembly.

Figure 6-5. Reference Thermal Solution





6.2 Environmental Reliability Requirements

The reference solution heatsink will be evaluated to the reliability requirements in Table 6-1. The mechanical loading of the component may vary depending on the heatsink, and attach method used. The customer should define a validation test suite based on the anticipated use conditions and resulting reliability requirements. Thermal cycling, bake and humidity tests were performed on original design and are not being repeated. The designer should select appropriate thermal / humidity tests for the expected use conditions.

Table 6-1. Reference Thermal Solution Environmental Reliability Requirements

Test	Requirement	Pass / Fail Criteria
Mechanical Shock	3 drops for + and - directions in each of 3 perpendicular axes (that is, total 18 drops). Profile: 50 G trapezoidal waveform, 170 inches/sec. minimum velocity change. Setup: Mount sample board on test fixture	Visual\Electrical Check
Random Vibration	Duration: 10 min/axis, 3 axes Frequency Range: 5 Hz to 500 Hz Power Spectral Density (PSD) Profile: 3.13 g RMS	Visual\Electrical Check

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Appendix A Thermal Solution Component Vendors

Note: These vendors and devices are listed by Intel as a convenience to Intel's general customer base, but Intel does not make any representations or warranties whatsoever regarding quality, reliability, functionality, or compatibility of these devices. This list and/or these devices may be subject to change without notice.

Table A-1. Reference Heatsink Enabled Components

Item	Intel PN	AVC	CCI	Foxconn	Wieson
Heatsink Assembly	C46655-001	S702C00001	00C855802B	2Z802-009	
Anchor	A13494-008			HB9703E-DW	G2100C888-064H

Table A-2. Supplier Contact Information

Supplier	Contact	Phone	Email
AVC* (Asia Vital Corporation)	Kai Chang	+86 755 3366 8888 x63588	kai_chang@avc.com.tw
CCI* (Chaun Choung Technology)	Monica Chih	+886-2-2995-2666 (714) 739-5797	monica_chih@ccic.com.tw hlinack@aol.com
Foxconn*	Jack Chen Wanchi Chen	(408) 919-6121 (408) 919-6135	jack.chen@foxconn.com wanchi.chen@foxconn.com
Wieson*	Chary Lee Henry Liu	+886-2-2647-1896 ext. 6684 +886-2-2647-1896 ext.6330	chary@wieson.com henry@wieson.com

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Appendix B Mechanical Drawings for Package and Reference Thermal Solution

The mechanical drawings included in this appendix:

Figure B-1, "Intel® 7 Series Chipset and Intel® C216 Chipset Package Drawing" on page 28.

Figure B-2, "Motherboard Keep-Out for ATX Reference Heatsink" on page 29.

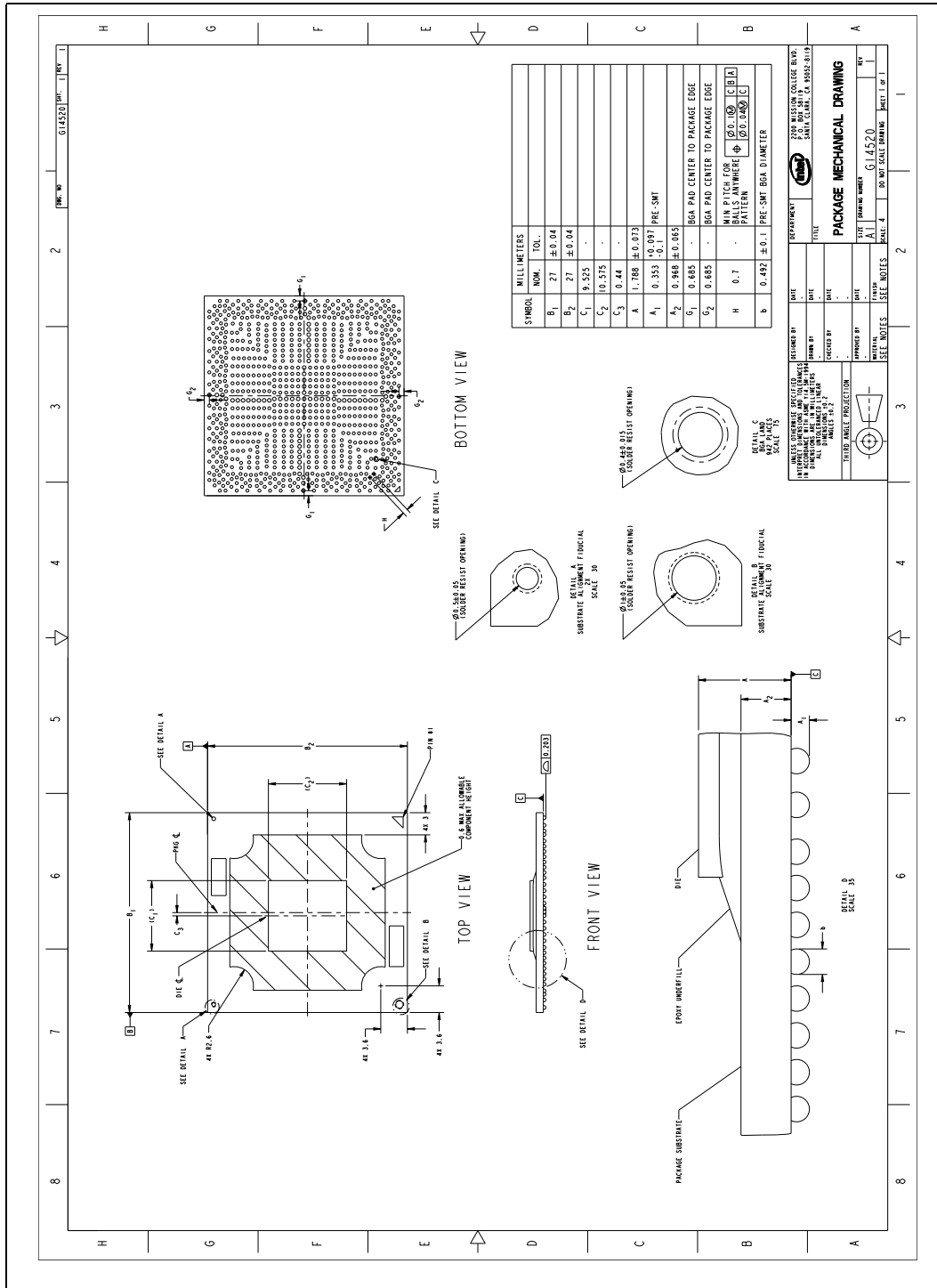
Figure B-3, "ATX Reference Heatsink Assembly" on page 30.

Figure B-4, "ATX Reference Heatsink Extrusion" on page 31.

Figure B-5, "ATX Reference Heatsink Clip" on page 32.



Figure B-1. Intel® 7 Series Chipset and Intel® C216 Chipset Package Drawing



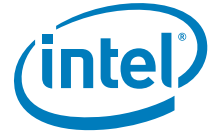


Figure B-2. Motherboard Keep-Out for ATX Reference Heatsink

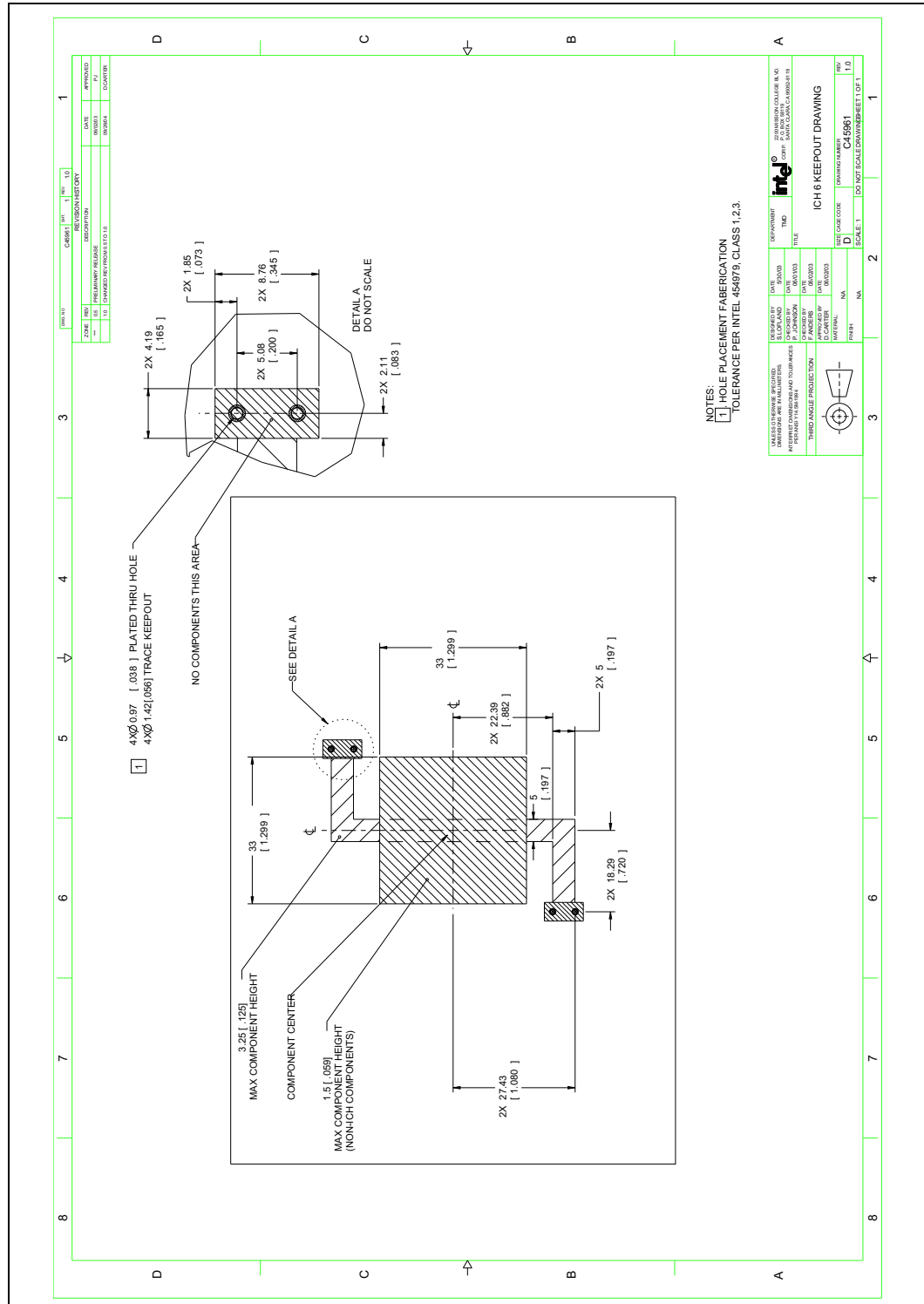
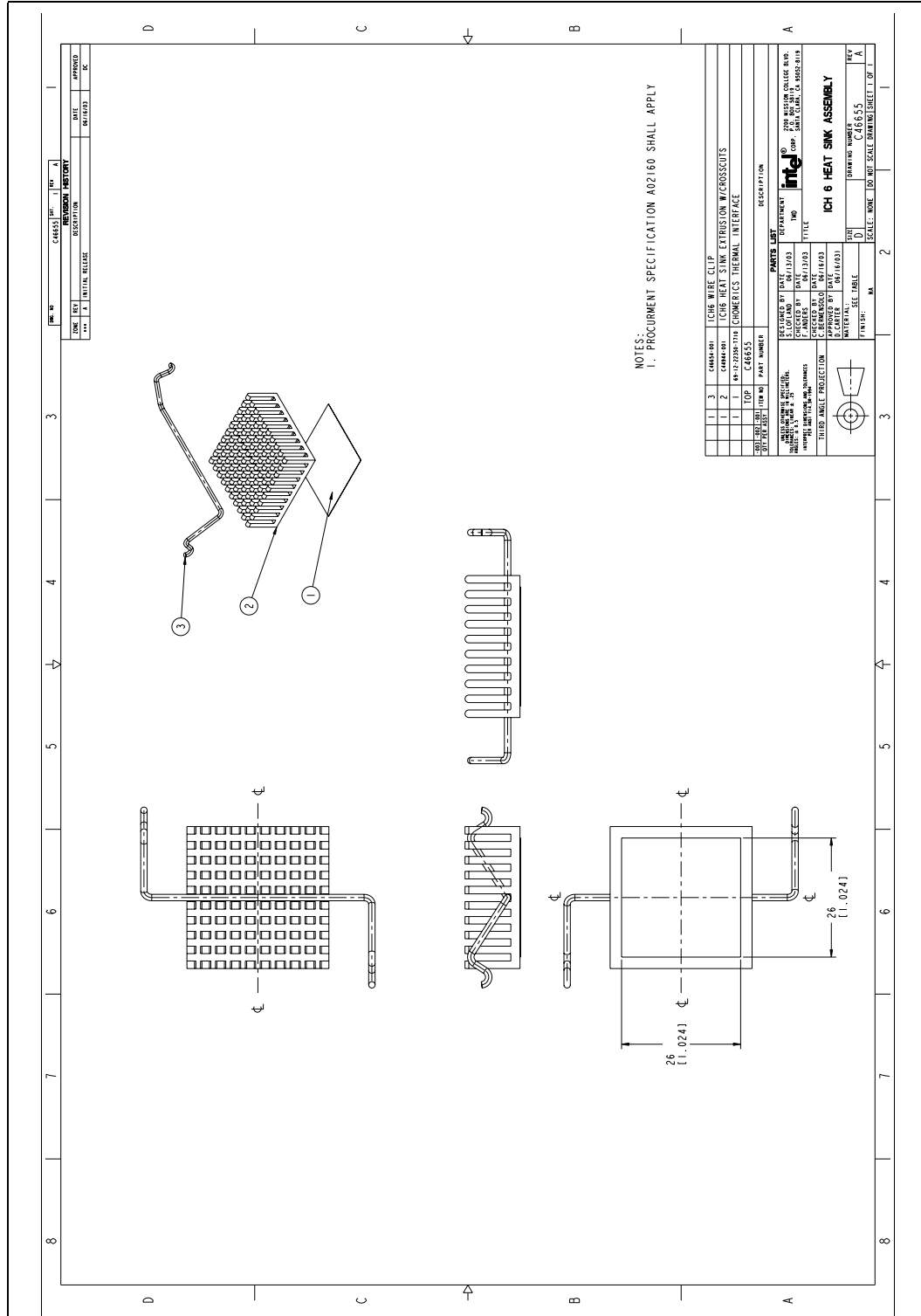


Figure B-3. ATX Reference Heatsink Assembly



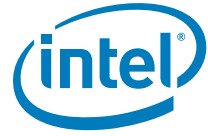


Figure B-4. ATX Reference Heatsink Extrusion

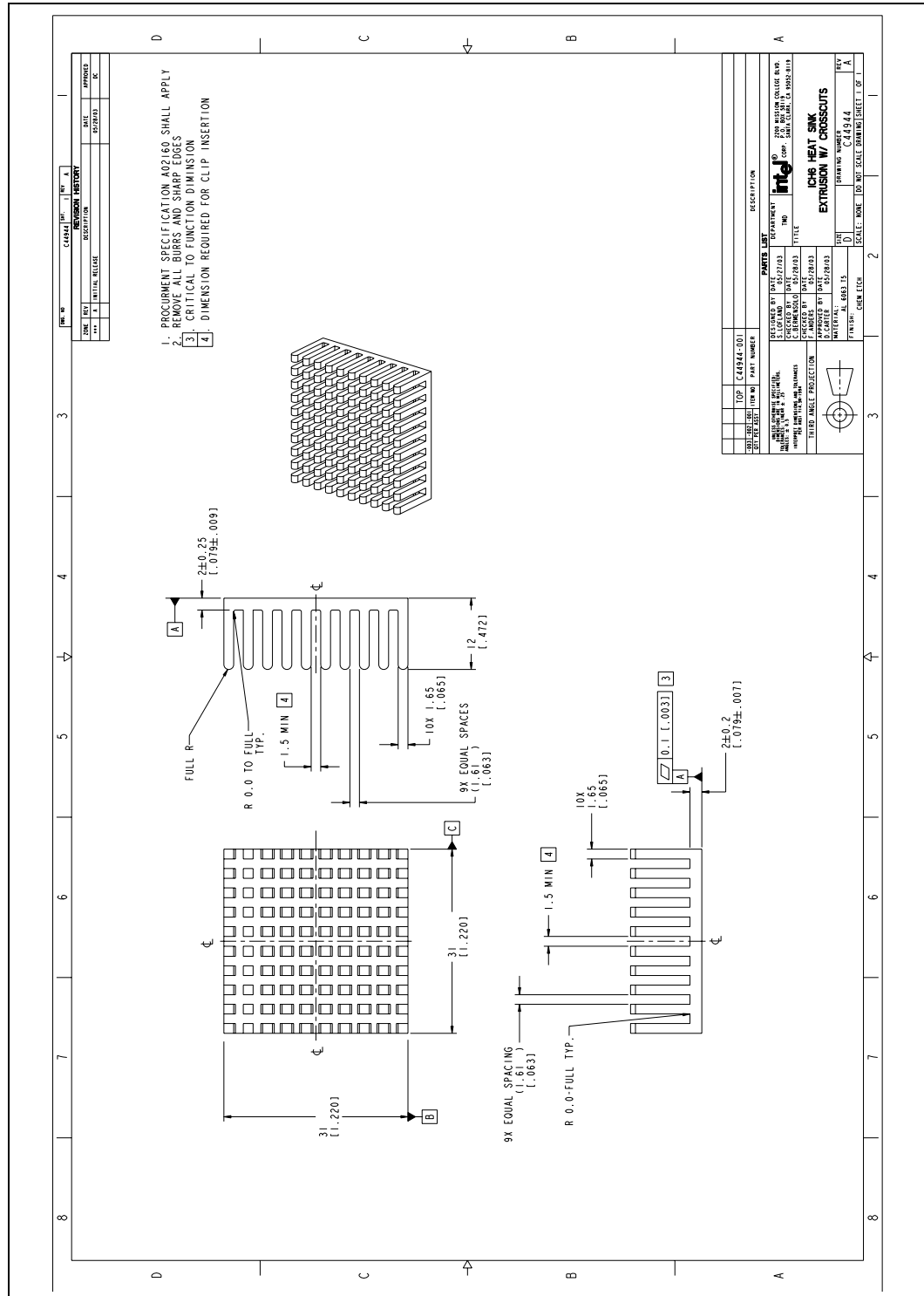
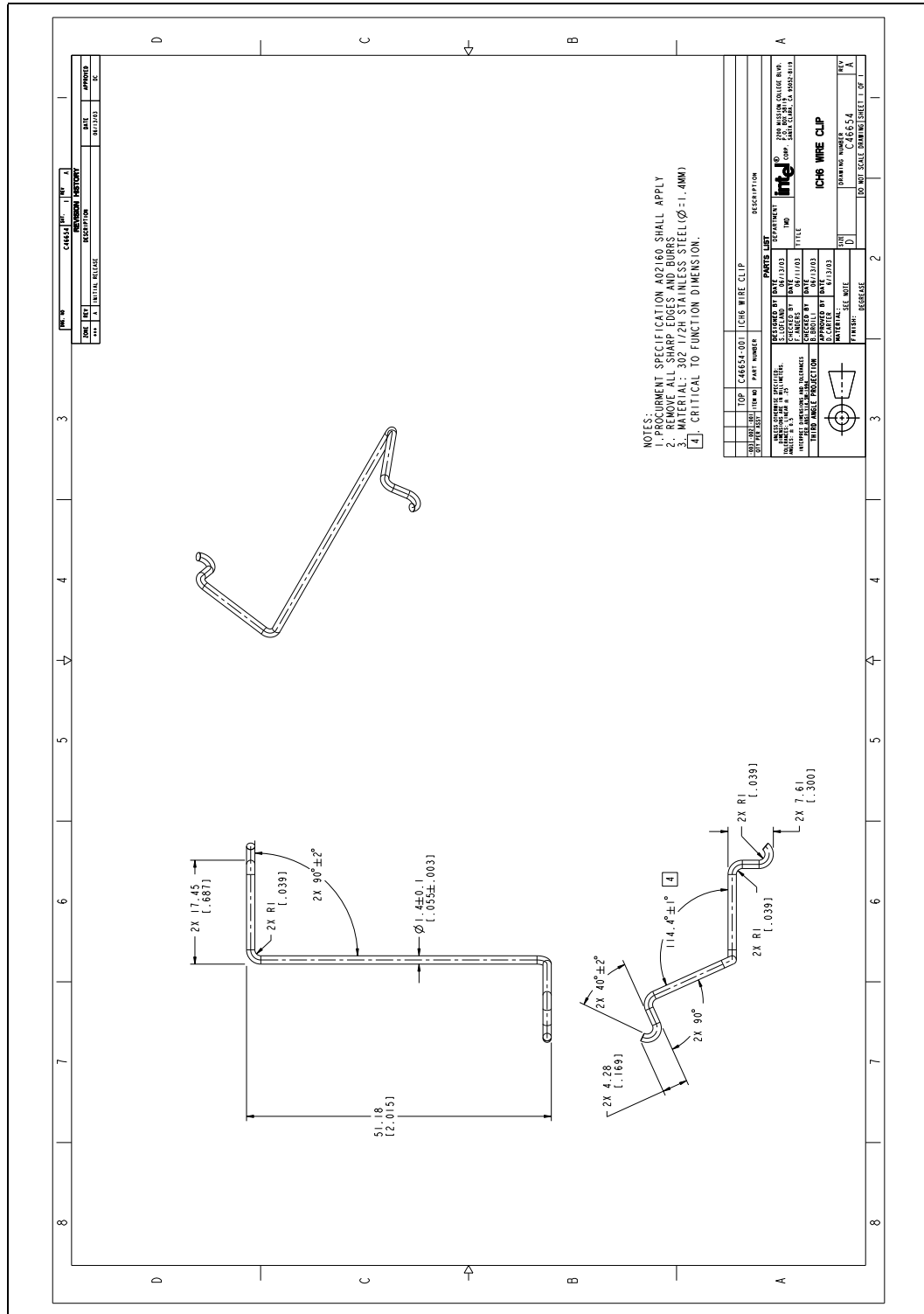


Figure B-5. ATX Reference Heatsink Clip



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